Tool Make & Model

Tool Configuration / Specifications

InSight CAP 200mm DUAL Front (in-line) SMIF load-ports
Model SPC-201123-XX, InSight CAP (Compact Atomic Force Profiler) with
Dual In-line SMIF Load Port with automated loading
Designed specifically for automated production measurement of critical CMP parameters such as dishing, erosion, and etch depth for semiconductor & data storage environments.

Includes the following:

Advance Roughness Package for Insight CAP (Compact Atomic Force Profiler)

- TrueSense™ mode, enables highest precision quantitative roughness down to the bare Si wafer level
- Active Vibration Insulation System, up to 20 dB isolation allow installation in VCC environment without performance degradation

Advanced Tip Qualification Software Option for Insight CAP (Compact Atomic Force Profiler)

- Tip shape characterization for automatically determining tip effective length and width in the Y-axis (90-degrees)
- Tip characterizer standards (Model I2FSR, Shape Characterizer; Model IVPS100A, Tip Width Calibration Structure)
- Advanced TIP qualification software key
- MUST be purchased initially with the system

Sidewall Characterization with 3D Sidewall Characterization Software

- 3D sidewall characterization Mode for INSIGHT CAP
- 3D sidewall characterization software for InSight CAP
- MUST be purchased initially with the system

Photo Ionizer for INSIGHT CAP (Compact Atomic Force Profiler)

- Replace Polonium source (current standard) with Photo Ionizer

Browse our site at www.moov.co

The information contained in this data sheet is, to our knowledge, accurate. We do not warrant the completeness or accuracy of the information contained herein. Any offer by you to purchase the equipment described in this data sheet shall be subject to the terms and conditions of sale.

Tool Configuration / Specifications

- Designed to meet SEMI S2 standards

Atomic Force Profiler Specifications

- 100mm Long Scan Profiling includes up to 25M points/line
- Depth Metrology AFM Head >100-micron x >100-micron AFM X,Y scan range and vertical range of 15 microns with closed loop independent control with up to 25 million pixels per image (maximum of 5k x 5k image)
- NanoScope V 64-bit Metrology Control Station

Wafer Handling Specifications

- Precision and programmable X-Y stage with vacuum chuck to handle wafers/substrates up to 200mm diameter. Stage travel is minimum 200mm x 200mm.
- Pre-aligner and robot for automated control of 200mm wafers
- Qty: Dual in-line SMIF load ports for 200mm
- Particle control microenvironment is mounted inside AFM acoustic enclosure, with computer-controlled fan/filter system to maintain ISO Class 3 air inside AFM acoustic enclosure.

Registration Optics Specifications

- Integrated top-view video optics allows cantilever viewing on-axis in real time during scans
- NanoScope Vision System provides for recognition and scanning of learned patterns on wafers and allows system to automatically locate measurement sites without operator alignment.
- Includes PatMax and CVL Optical Pattern Recognition system with integrated high and low magnification cameras
- Pattern recognition optics with up to 6mm x 5mm FOV

Software Specifications

- NanoScope Version 8.91 Software provides easy-to-use recipe generation and wafer navigation including:
  1. Dishing and Erosion Analysis Software
  2. NanoScope recipe teach allows users to automate repetitive sample scanning with automated recipes. Including automated wafer handling and registration, measurement, data processing and reporting.
  3. Tip and Cassette Management
  4. Captive Sample Management

Probe Control Specifications

- Enhanced TipX Automatic Tip Exchange and Optics for automatically changing the probe without operator intervention
- Two standard TipX tip cassettes that hold up to 24 probes each.

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